

TESTFORUM 2019

Sokos Hotel Viru, Tallinn, Estonia November 26th – 27th, 2019

NTF Chairman

Knut Båtstoløkken Kitron, Norway

Financial Chair

Birger Schneider CHAMAJ Consult, Denmark

Secretary Chair

Bjørn B Larsen NTNU, Norway

Marketing Chair

Lars Kongsted-Jensen EP-TeQ, Denmark

Executive Committee Members

Knut Båtstoløkken Kitron, Norway

Birger Schneider CHAMAJ Consult, Denmark

Bjørn B Larsen NTNU, Norway

Stig-Gunnar Jensen Eltek, Norway

Artur Jutman Testonica Lab, Estonia

Mick Austin JTAG Technologies, Finland

Erik Larsson Lund University, Sweden

Lars Kongsted-Jensen EP-TeQ, Denmark

Magnus Rönnqvist Syntronic Test Systems, Sweden

Mauri Aalto Neste Engineering Solutions, Finland

Paulius Musteikis UAB Kitron, Lithuania

Mikko Karjalainen KaVo Kerr, Finland

Mattias Ericsson AddQ. Sweden

Thomas Goetz (associate member) Keysight Technologies, Germany

Test Forum 2019 Local Organizer

Artur Jutman Testonica Lab, Estonia Phone: +372 620 2246 E-mail: artur@testonica.com

Nordic Test Forum

Call for Papers & Presentations

The 2-day TestForum 2019, the 20th event in the series, is the major event for Test professionals in the Nordic area and the Baltic states. Every year the TestForum is attended by key people from the industrial test community as well as by international vendors of test and measurement equipment and solutions.

This year the event will take place in downtown Tallinn, at a very close proximity to the UNESCO Heritage medieval core of the city – the Old Town.

Nordic Test Forum hereby cordially invites you to participate and submit your contribution to TestForum 2019, which includes (but is not limited to) the following topics:

- Functional Test
- Boundary Scan
- Embedded Instruments
- RF Testing
- AOI/AXI/SPI
- ICT / Flying Probe
- Test Economics
- Power Test
- Fixturing/Interfaces
- Future technology trends and test challenges
- Best practices in manufacturing test
- ASIC: BIST / Mixed-signal / IDDQ / IDDT
- Board test SW, BIST, diagnostics
- Quality methods and tools
- · Robotics in testing
- Preventive test / Prognostics
- Design to Test transfer / Design for Test
- Test efficiency and optimization
- Big Data acquisition / collection / analysis

Submissions

TestForum seeks presentations (and/or short papers) in the area of test of electronics, including *R&D*, *Application Contributions*, *Best Practices*, *Emerging Ideas*, etc. You are welcome to submit contributions also outside the above topics as long as they stay within the field of electronics test. Focus shall be on new and upcoming challenges, opportunities, techniques and best practices in electronics test technology rather than on particular products. Submission format: up to half-page abstract of the proposed contribution is sufficient for selection process.

Proceedings

The accepted contributions of authors that wish to provide the corresponding materials will be delivered in electronic format at the Nordic Test Forum event.

The Format of the Event

- The event format is a two-day workshop and a small exhibition attached to it.
- November 25th in the evening there is the Annual General Meeting of the NTF.
- The number/duration of sessions is defined by the mix of presentations (approx. 20).
- The presentations are 30 minutes each: 25 minutes of speech and 5 minutes for Q&A.
 Companies are invited to arrange table-top demos at the exhibition area, where a table will
- be provided to exhibitors.

 In the exhibition, attendees will have a chance to see the latest equipment and talk to
- In the exhibition, attendees will have a chance to see the latest equipment and talk to exhibitors.

Key Dates

- Abstract submission:
- Notification of acceptance:
- Conference registration opens:
- Presentation slides:

31st August

6th September

16th September

1st November

Further Information and Submissions

Jytte Schneider

Phone: +45 2579 1120

Email: jytte.schneider@nordictestforum.org

Visit the NTF web pages at http://www.nordictestforum.org







